

Substitute for form 1449A&B/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)				Complete if Known	
				Application Number	10/509656
				Filing Date	
				First Named Inventor	Toshio Goto
				Art Unit	
				Examiner Name	
Sheet	1	of	1	Attorney Docket Number	

U.S. PATENT DOCUMENT					
Examiner Initials*	Cite No. ¹	Document Number		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
		Number	Kind Code ² (if known)		
		US			
		US			
		US			

FOREIGN PATENT DOCUMENT							
Examiner Initials*	Cite No. ¹	Foreign Patent Document			Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Translation ⁶
		Country Code ³	Number ⁴	Kind Code ⁵ (if known)			
✓		JP	06-293960	A	10-21-1994	MATSUSHITA ELECTRIC IND CO LTD	Abstract
✓		JP	3162623	B	02-23-2001	TOKYO ELECTRON LTD	Abstract
✓		JP	04-053947	B	08-28-1992	NIPPON STEEL CORP	Abstract
✓		JP	04-081132	B	12-22-1992	HOKAIDO UNIV	Abstract
✓		JP	10-083893	A	03-31-1998	SONY CORP	Abstract
✓		JP	62-054871	B	11-17-1987	AGENCY OF IND SCIENCE & TECHNOL	Abstract

OTHER PRIOR ART—NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	Translation ⁶
✓		Kono et al., "Plasma Absorption Spectroscopy Using Microdischarge Light Source" (May 2000)	Abstract
✓		Ohta et al., "Behaviors of Si, SiF, SiF ₂ radicals and SiF ₄ molecule in RF60MHz capacitively coupled SiF ₄ plasma", Proceedings of International Symposium on Dry Process, The Institute of Electrical Engineer of Japan, October 10 - 11, 2002	Abstract
✓		Ohta et al., "The effect of driving frequency on the behavior of Si atoms in capacitively coupled VHF SiF ₄ plasma", Proceedings of the 20 th Symposium on Plasma Processing, Division of Plasma Electronics, The Japan Society of Applied Physics, January 29 - 31, 2003	Abstract

Examiner Signature		Date Considered	12-22-06
--------------------	---	-----------------	----------

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹Applicant's unique citation designation number (optional). ²See Kind Codes of USPTO Patent Documents at www.uspto.gov, MPEP901.04 or in the comment box of this document. ³Enter office that issued the document, by the two-letter code (WIPO Standard ST.3) ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶Applicant is to indicate here if English language Translation is attached.

Best Available Copy

Substitute for form 1449A&B/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(use as many sheets as necessary)</i>				Complete if Known	
				Application Number	
				Filing Date	
				First Named Inventor	
				Art Unit	
Examiner Name				Toshio Goto	
Sheet	1	of	1	Attorney Docket Number	

U.S. PATENT DOCUMENT					
Examiner Initials*	Cite No. ¹	Document Number		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
		Number	Kind Code ² (if known)		
		US			
		US			
		US			
		US			
		US			
		US			

FOREIGN PATENT DOCUMENT							
Examiner Initials*	Cite No. ¹	Foreign Patent Document			Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Translation ⁶
		Country Code ³	Number ⁴	Kind Code ⁵ (if known)			

OTHER PRIOR ART-NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	Translation ⁶
R		Kikukawa et al., "Microcrystalline Silicon Thin Film Formation Using a Low Pressure Microwave Plasma", the 62 nd Symposium of the Society of Applied Physics, Digest 14a-ZF-3, September 2001, pp. 736	

Examiner Signature	<i>R. Goto</i>	Date Considered	12-22-06
--------------------	----------------	-----------------	----------

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹Applicant's unique citation designation number (optional). ²See Kinds Codes of USPTO Patent Documents at www.uspto.gov, MPEP 901.04 or in the comment box of this document. ³Enter office that issued the document, by the two-letter code (WIPO Standard ST.2). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶Applicant is to indicate here if English language Translation is attached.

Best Available Copy



Approved for use through 07/31/2006. OMB 0651-0031
U.S. Patent and Trademark Office: U.S. DEPARTMENT OF COMMERCE

Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number.

Substitute for form 1449A/PTO

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(use as many sheets as necessary)

Sheet

1

of

1

Complete if Known

Application Number	10/509,656
Filing Date	September 29, 2004
First Named Inventor	Toshio GOTO
Art Unit	2812
Examiner Name	Unassigned
Attorney Docket Number	101250.55460US

U.S. PATENT DOCUMENTS[illegible]

FOREIGN PATENT DOCUMENTS

Examiner Initials ¹	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		Country Code ³ --Number ⁴ --Kind Code ⁵ (if known)				
M	AA	JP 2001-160552 A	08/12/2001	Applied Materials Inc.		AB

**Examiner
Signature**

Run

Date Considered

12-22-06

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. 1 Applicant's unique citation designation number (optional). 2 See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 801.04. 3 Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). 4 For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. 5 Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. 6 Applicant is to place a check mark here if English language Translation is attached.

This collection of information is required by 37 CFR 1.97 and 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 2 hours to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

If you need assistance in completing the form, call 1-800-PTO-9199 and select option 2.